

Joint ICTP-IAEA Advanced Workshop on High Sensitivity 2D & 3D
Characterisation and Imaging with Ion Beams | (smr 2856)

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Radiation damage during analysis

Thursday, 29 September 2016 11:00 (1:00)

Content

Ion beam analysis is a characterisation technique that is not deliberately destructive. However, an energetic beam of particles is used to probe the sample, and energy is deposited in the sample with a possibility to cause radiation damage during analysis. The question is, does it change the sample for analytical purposes? What is the damage mechanism and how it can be minimized.

Summary

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Session Classification : DAY 4